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Application No.	09905320	Prepared by	ewc
Examiner-GAU	Meeks	Date	1-20-04
	1762	No. of queries	- 1 -
		Tracking Number	05877423
		Week Date	12-15-03
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a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION		MESSAGE	
a. Page Missing		P70-1449	are illegible
b. Text Continuity		see	attached 11 sheets.
c. Holes through Data		Please supply	clear copies
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g. Brief Description			
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CLAIMS			
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1657	SERIAL NO. 09 905.320
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if needed)</small>				APPLICANT: Cam Basceri et al.	
				FILING DATE July 13, 2001	GROUP 1762

U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Applicable	
EF	01						
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FOREIGN PATENT DOCUMENTS							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
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EXAMINER <i>E. Tuller</i>	DATE CONSIDERED <i>9/4/02</i>
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22 2637	SERIAL NO. 6068 320
LIST OF ART CITED BY APPLICANT <small>(For record of art cited by applicant)</small>		APPLICANT Gen. Bascetta et al.	
		FILING DATE Jan. 15, 2001	GROUP I

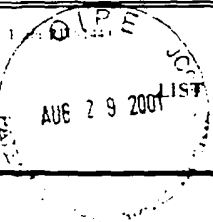
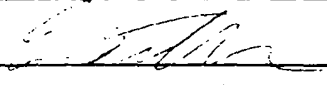
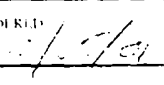
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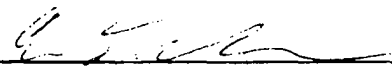
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
CF	AR		Kim, et al. <i>Structural and Electrical Properties of Bi₂O₃ grown on p-InP (100) by low-pressure metalorganic chemical vapor deposition at low temperature</i> . <i>Applied Physics Letters</i> , U.S. Antarctic Institute of Physics Vol. 65, No. 15, 10-10-94, Pgs. 1955-1957
	AS		
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EXAMINER 	DATE CONSIDERED 12/05/01
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with text communication to applicant.

		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22 1675		SERIAL NO. 00065320	
		LIST OF ART CITED BY APPLICANT <small>(Use serials cited in Remarks)</small>					
		APPLICANT Sanyo Electric Co., Ltd.		FILING DATE July 23, 2002		GROUP I, Class 360	
U.S. PATENT DOCUMENTS							
Sequence Number	Document Number	Date	Name	Class	Subclass	Translation	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
EF	AK	S. Yamamichi et al., Abstract, <i>Ba-Sr-Ti ratio dependence of the dielectric properties for (Ba_{1-x}Sr_x)TiO₃ thin films prepared by ion beam sputtering</i> , 63 APPLIED PHYSICS LETTERS No. 13, pp. 1644-1646 (1994).					
EF	AS	M. Yamamichi et al., Abstract, <i>Thermal-Desorption Spectroscopy of (Ba_{1-x}Sr_x)TiO₃ Thin Films Prepared by Chemical Vapor Deposition</i> , 35 JPN. J. OF APPL. PHYS. Pt. 1, No. 2A, pp. 729-735 (1996).					
EF	AT	Arai T. et al., <i>Preparation of SrTiO₃ Films on Si/SiO₂ Wafers by Chemical Vapor Deposition</i> , Jap. Journal of Applied Physics, Vol. 35, No. 9B, Part 02, pp. 4875-4876.					
EXAMINER				DATE CONSIDERED			
							
<small>*EXAMINER: Initial reference considered, whether or not citation is in accordance with MPEP 609. Draw line through citation if not in conformity and not considered. Include a page reference with each citation in applicant's copy.</small>							

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M1221967		SERIAL NO. 00968326			
<div style="display: flex; align-items: center;"> <div style="border: 1px solid black; border-radius: 50%; padding: 5px; margin-right: 10px;"> AUG 29 2001 </div> <div> LIST OF ART CITED BY APPLICANT <small>(use several sheets if necessary)</small> </div> </div>				APPLICANT Gen Baset et al.			
FILING DATE July 15, 2001				GROUP Unknown			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Title	Class	Subclass	Filing Date If Appropriate	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
EF	AR		Takaaki Kawahara et al., (Ba, SrTiO ₃) Films Prepared by Liquid Source Chemical Vapor Deposition on Ru Electrodes, 35 Jpn. J.				
			AIE, PHYS. PL. 1, No. 9B, pp. 4880, 4883 (1996)				
LF	AS		Rajesh Khumarkar et al., A Novel Low-Temperature Process for High Dielectric Constant BST Thin Films for 1T1M DRAM				
			Applications, Microelectronics Research Center, Univ. of Texas at Austin, TX (Undated), 2 pages				
CF	AT		Yong Tae Kim et al., Abstract, Advantages of Ru ²⁺ bottom electrode in the dielectric and leakage characteristics of				
			(Ba SrTiO ₃) capacitor, 35 Jpn. J. AIE, PHYS. PL. 1, No. 12A, pp. 6153-6156 (1996)				
EXAMINER			DATE CONSIDERED				
			12/05/01				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Induce copy of this form with next communication to applicant.</small>							

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPL. DOCKET NO. M122 1657	SERIAL NO. 00 908 320
LIST OF ART CITED BY APPLICANT <small>Use serial sheets if necessary</small>		APPLICANT Gen. Electric Co.	
		FILING DATE 12/15/2000	GROUP 1

U.S. PATENT DOCUMENTS							
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OTHER REFERENCES - including Author, Title, Date, Pertinent Pages, Etc.			
LF	NR		S.H. Park et al., Abstract, <i>Characterization of MIS capacitor of BST thin films deposited on Si by RF magnetron sputtering</i> Ferroelectric Thin Films V, Scarsdale, San Francisco, CA, pp. 33-38 (April 7, 1995)
LF	AS		N. Takeuchi et al., Abstract, <i>Effect of firing atmosphere on the cubic-tetragonal transition in Bi_{1-x}Sm_xTiO₃ (0.0 ≤ x ≤ 0.08)</i> SIYAKUOKU KYOKAI GAKUJIN RONBUNSHU No. 5, pp. 539-549 (1996)
EF	AI		H. Yamaguchi et al., Abstract, <i>Reactive coevaporation synthesis and characterization of SrTiO₃/BaTiO₃ thin films</i> , IEEE International Symposium on Applications of Ferroelectrics, Greenville, SC, pp. 285-288 (August 2, 1992)

EXAMINER 	DATE CONSIDERED 12/15/01
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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LIST OF ART CITED BY APPLICANT

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U.S. PATENT DOCUMENTS

Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Applicable
EE	AA			Cem Bascer et al as filed			Filed Concurrently
EE	AB	09 476 515		Cem Bascer as filed and as amended			01 03 00
EE	AC	09 580 733		Cem Bascer as filed			05 26 00
EE	AD	5 459 625	10 17 95	Tomczawa et al	361	321.5	
EE	AE	5 618 761	04 08 97	Eguchi et al	438	785	
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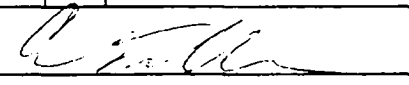
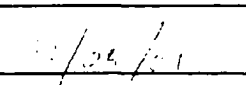
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPY. DOCKET NO. M22-1557		SERIAL NO. 06/004320	
LIST OF ART CITED BY APPLICANT (on several sheets if necessary)				APPLICANT Cem Basem et al.			
				FILING DATE 12/12/2007		CLASS H01L 27/00	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Title	Class	Subclass	Filing Date If Applicable
E	AA	5,296,485	10/26/93	Nakamura			
E	AB	5,751,948	01/21/97	Endo			
E	AC	5,776,254	03/24/98	Yabuzo et al.			
E	AD	5,785,254	07/07/98	Yusui et al.			
E	AE	5,798,935	07/21/98	Roh			
E	AF	6,043,520	08/25/98	Dhali et al.			
E	AG	6,046,340	03/28/00	Ochiai			
E	AH	6,078,492	04/04/00	Kadokura et al.			
E	AI	6,153,895	06/20/00	Hama et al.			
E	AJ	6,037,209	11/28/00	Watanabe			
E	AK	6,037,205	03/14/01	Huh et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
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E	AL	0,855,758 A2	26/01/98	EPO - Zhao et al., Applied Materials, Inc.			
E	AM	0,957,522 A2	12/05/99	EPO - Ueda, Matsubara, Matsubara Electric Ind. Co.			
E	AN	WO 98/04097	20/02/98	WIPO - Simpson, John et al.			
E	AO	0,474,140 A1	30/08/91	EPO - Kamayama, Satoshi et al., NEC Corporation			
E	AP	WO 99/44645	11/06/99	WIPO - Narwankar et al., Applied Materials, Inc.			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
E	AR			Steve Bilodeau et al., <i>Composition Dependence of the Dielectric Properties of MOCVD Ba-Sr LTO</i> , pp. 1-21, MRS Fall Meeting, 12/01/94			
E	AS			Steve M. Bilodeau et al., <i>MOCVD EML for High Density DRAM Applications</i> (Preprint for SEMICONWEST 07/12/95), 2 pages			
E	AT			Y. C. Zeng et al., <i>Abstract, Improvements in the Properties of Chemical Vapor-Deposited (Ba,Sr)F₂ Films Through Use of a Seed Layer</i> , 6 JIN J. APPL. PHYS. Pt. 1, No. 11, pp. 6824-6828 (1997)			
EXAMINER				DATE CONSIDERED			
							
<small>*EXAMINER: Initial reference considered, whether or not citation is in compliance with MPEP 609. If a line through citation is not in compliance and not considered, include copy of this form with text communicating to applicant.</small>							

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLY DOCKET NO. MI22-1657		SERIAL NO. 09,905,320			
<div style="text-align: center;"> LIST OF ART CITED BY APPLICANT <small>Use separate sheets if necessary</small> </div>				APPLICANT Chun-Bao Chen et al.			
FILING DATE 12/15/2007				GROUP 1			
<div style="text-align: center;">U.S. PATENT DOCUMENTS</div>							
Examiner's Initial	Docket Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
EF	AA	5,475,395	11/28/95	Shimizu et al.			
EF	AI	5,254,505	10/19/93	Kameyama			
EF	AI	6,156,658	12/05/00	Agarwal et al.			
EF	AI	6,165,834	12/26/00	Agarwal et al.			
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<div style="text-align: center;">OTHER REFERENCES (including Author, Title, Date, Page(s), etc.)</div>							
EF	AI		Chung-Ming Chu et al., Abstract, <i>Electrical properties and crystal structure of (Ba_{1-x}La_x)TiO₃ films prepared at low temperatures</i>				
			on a LaTiO ₃ electrode by radio-frequency magnetron sputtering, JOURNAL OF APPLIED PHYSICS, Vol. 79, No. 2, pp. 249-251 (1997).				
EF	AI		Kazuhito Iguchi et al., Abstract, <i>Chemical vapor deposition of (Ba_{1-x}La_x)TiO₃ thin films for application in gigabit scale</i>				
			dynamic random access memories, 14 INTEGRATED FERROELECTRICS Nos. 1-4, Pt. 1, pp. 33-42 (1997).				
EF	AI		Q.N. Jia et al., Abstract, <i>Structural and dielectric properties of Ba_{1-x}La_xTiO₃ thin films with an (a) RuO₂ bottom electrode</i>				
			19 INTEGRATED FERROELECTRICS Nos. 1-4, pp. 111-119 (1998).				
EXAMINER			DATE CONSIDERED				
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<small>*EXAMINER: If not a reference considered, whether or not citation is in compliance with MPEP 609. Draw line through citation if not in compliance and not considered. Include cross-reference to this form with next communication to applicant.</small>							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1657		SERIAL NO. 09/905,320	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Cem Basceri et al.			
				FILING DATE July 13, 2001		GROUP 1782	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
EF	AA	5,596,316	01-1997	Endo	257	324	
	AB						
EF	AC	09/344,080		Agarwal et al. (As Amended in response to 09/29/01 Office Action; 12/30/00 Office Action, and 11/29/01 Office Action)			August 20, 1999
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EXAMINER <i>E. J. Smith</i>				DATE CONSIDERED 9/30/02			
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICATION NO. 02/017,007		SECTION 1 INFORMATION	
LIST OF APPLICANT'S APPLICANTS				APPLICANT'S NAME: [Blank]			
APPLICANT'S ADDRESS: [Blank]				APPLICANT'S CITY: [Blank]			
APPLICANT'S COUNTRY: [Blank]				APPLICANT'S PHONE: [Blank]			

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Serial No.	Class	Inventor's Name	Title	Priority	Class	Subclass	Translation	
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1	35	John Doe	Method of doing business	12/01	35	200		
2	35	John Doe	Method of doing business	12/01	35	200		
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OTHER REFERENCES (including Author, Title, Date, Inventor, Pages, Etc.)			
1	35	Reference to the invention as a method of doing business, U.S. Patent No. 1,234,567, 1/1/01, 10 pages.	
		Reference to the invention as a method of doing business, U.S. Patent No. 1,234,567, 1/1/01, 10 pages.	
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EXAMINER: [Signature]	DATE CONSIDERED: 3/1/02
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EXAMINER: [Signature] is hereby notified that the application is being examined under the provisions of the Patent and Trademark Office's "Examination of Applications for Patents" (PTO 1000) and the "Examination of Applications for Trademarks" (PTO 1000).

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